



Short Course on Microwave Measurements

Dec. 1 – 2, 2009
Broomfield, Colorado



AGENDA

Tuesday, December 1

- 7:30 a.m. – 8:00 a.m. **Registration**
- 8:00 a.m. – 8:10 a.m. **Welcome and Introduction**
Dominique Schreurs – K.U.Leuven
- 8:10 a.m. – 9:10 a.m. **Connectorized S-Parameter Measurements**
Jon Martens – Anritsu
- 9:10 a.m. – 10:10 a.m. **On-Wafer S-Parameter Measurements**
Dylan Williams – NIST
- 10:10 a.m. – 10:30 a.m. **Break**
- 10:30 a.m. – 11:30 a.m. **Large-Signal Measurements**
Dominique Schreurs – K.U.Leuven
- 11:30 a.m. – 12:30 p.m. **High Speed Oscilloscope Measurements**
Paul Hale – NIST
- 12:30 p.m. – 1:30 p.m. **Lunch**
- 1:30 p.m. – 2:30 p.m. **Microwave Power Measurements**
Tom Crowley – NIST
- 2:30 p.m. – 3:30 p.m. **Microwave Thermal Noise Measurements**
David Walker – NIST
- 3:30 p.m. – 4:00 p.m. **Break**
- 4:00 p.m. – 5:00 p.m. **Phase Noise Measurements**
Craig Nelson – NIST



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AGENDA

Wednesday, December 2

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| 8:00 a.m. – 9:00 a.m. | Measurement Uncertainty <i>Nick Ridler – NPL</i> |
| 9:00 a.m. – 10:00 a.m. | Uncertainty of Complex-Valued Measurement Quantities <i>Blair Hall – IRL</i> |
| 10:00 a.m. – 10:20 a.m. | Break |
| 10:20 a.m. – 11:20 a.m. | Uncertainties in On-Wafer S-parameter Measurements <i>Uwe Arz – PTB</i> |
| 11:20 a.m. – 12:20 p.m. | Measurement Verification <i>Ron Ginley – NIST</i> |

Contact

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